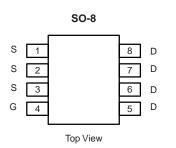
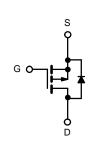


P-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)		
	0.015 at V _{GS} = - 4.5 V	- 13 ^a			
- 20	0.026 at $V_{GS} = -2.5 \text{ V}$	- 10 ^a	20 nC		
	0.065 at V _{GS} = - 1.8 V	- 8			





P-Channel MOSFET

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % R_g Tested Built in ESD Protection with Zener Diode
- Typical ESD Performance: 1800 V
- Compliant to RoHS Directive 2002/95/EC

HALOGEN **FREE**

APPLICATIONS

- Portable Devices
 - Load Switch
 - Battery Switch
 - Charger Switch

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 20	V	
Gate-Source Voltage		V_{GS}	± 12	v
	T _C = 25 °C		- 13 ^a	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	I_	- 10 ^a	
Continuous Diam Current (1) = 130 C)	T _A = 25 °C	I _D	- 8 ^{b, c}	
	T _A = 70 °C		- 7.1 ^{b, c}	A
Pulsed Drain Current		I _{DM}	- 50	\neg
Continuous Source-Drain Diode Current	T _C = 25 °C	I_	- 6 ^a	
Continuous Codice Diam Diode Current	T _A = 25 °C	I _S	- 2.9 ^{b, c}	
	T _C = 25 °C		19	
Maximum Power Dissipation	$T_C = 70 ^{\circ}C$	P _D	12	W
Maximum Fower Dissipation	$T_A = 25 ^{\circ}C$	' D	3.5 ^{b, c}	
	T _A = 70 °C		2.2 ^{b, c}	1
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Temperatur		260		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, e}	t ≤ 5 s	R _{thJA}	28	36	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R _{th.IC}	5.3	6.5	7 0/11	

- a. Package limited.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 5 s.
- d. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- e. Maximum under Steady State conditions is 80 °C/W.



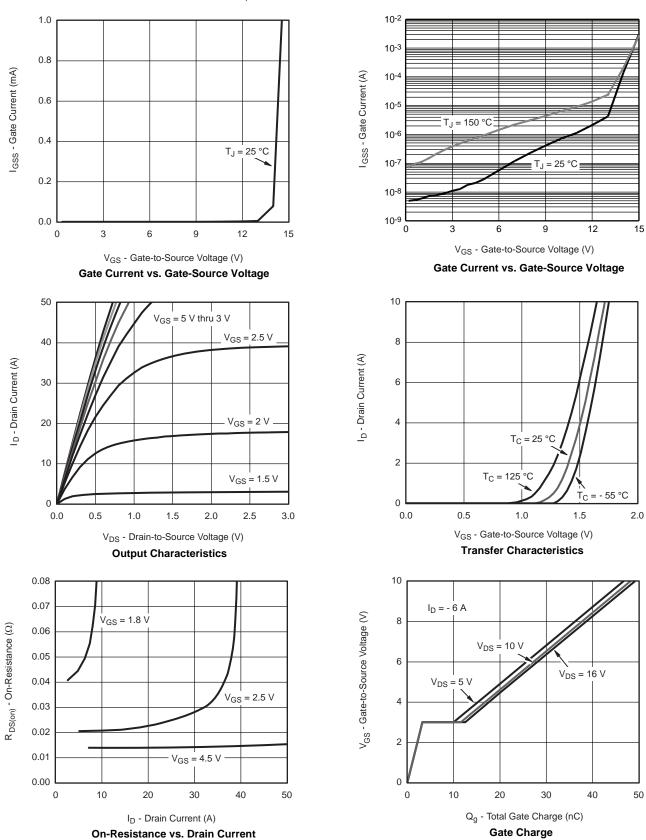
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				•		•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 20			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 12		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	i _D = - 250 μA		3			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 0.5		- 1.2	V	
Gate-Source Leakage	lass	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 20	20	
	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 4.5 \text{ V}$			± 0.5		
Zoro Gato Voltago Drain Current	lana	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$			- 1	μΑ	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	- 20			Α	
		V _{GS} = - 4.5 V, I _D = - 5.6 A		0.015	0.018	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 2.5 V, I _D = - 5.3 A		0.021	0.026		
		$V_{GS} = -1.8 \text{ V}, I_D = -2.5 \text{ A}$		0.040	0.065		
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 5.6 A		35		S	
Dynamic ^b	<u>'</u>			•	<u>'</u>	l .	
Total Gate Charge		V _{DS} = - 10 V, V _{GS} = - 8 V, I _D = - 5 A		50	75	nC	
Gate-Source Charge	Q_g			20	30		
	Q _{gs}	$V_{DS} = -10 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -5 \text{ A}$		3.3			
Gate-Drain Charge	Q_{gd}			8.4			
Gate Resistance	R_{g}	f = 1 MHz	0.2	1	2	kΩ	
Turn-On Delay Time	t _{d(on)}			0.71	1.1		
Rise Time	t _r	$V_{DD} = -10 \text{ V}, R_L = 1 \Omega$		1.7	2.6	_	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 5 A, V_{GEN} = - 4.5 V, R_g = 1		6	9		
Fall Time	t _f	Ω		3.2	5		
Turn-On Delay Time	t _{d(on)}			0.3	0.45	us	
Rise Time	t _r	V_{DD} = - 10 V, R_L = 1 Ω		0.6	0.9	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1$		10	15		
Fall Time	t _f	Ω		3.5	5.5	1	
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			- 6	Α	
Pulse Diode Forward Current	I _{SM}				- 50	_ ^	
Body Diode Voltage	V_{SD}	I _S = - 5 A, V _{GS} = 0 V		- 0.85	- 1.2	V	
Body Diode Reverse Recovery Time t _{rr}				30	60	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 6 A dl/dt = 100 A/us T = 25 °C		20	40	nC	
Reverse Recovery Fall Time	t _a	$I_F = 6 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		13		ns	
Reverse Recovery Rise Time	t _b			17			

Notes:

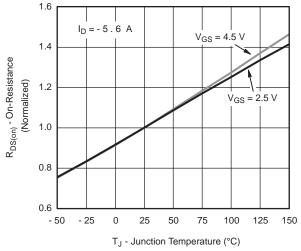
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$ b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

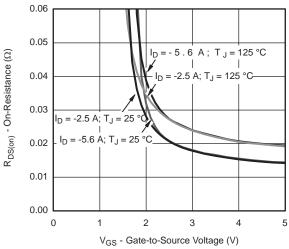




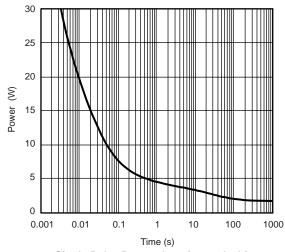




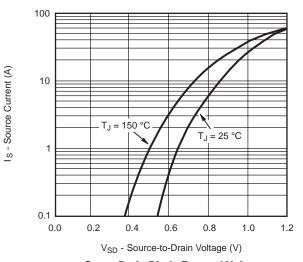
On-Resistance vs. Junction Temperature



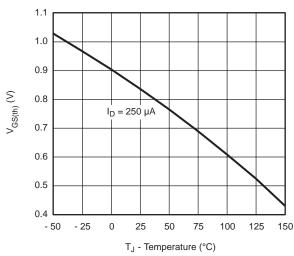
On-Resistance vs. Gate-to-Source Voltage



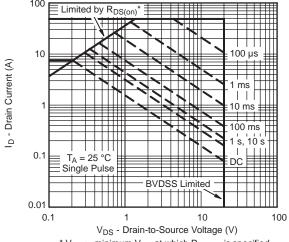
Single Pulse Power, Junction-to-Ambient



Soure-Drain Diode Forward Voltage



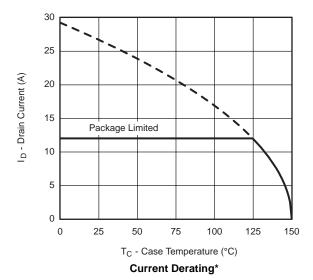
Threshold Voltage

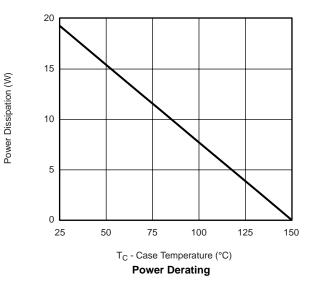


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

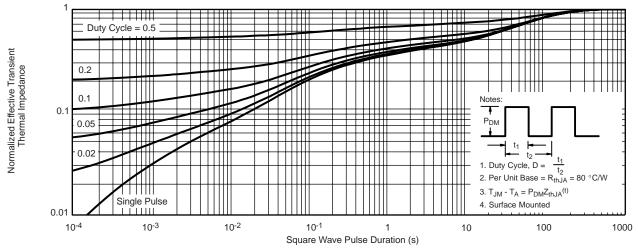




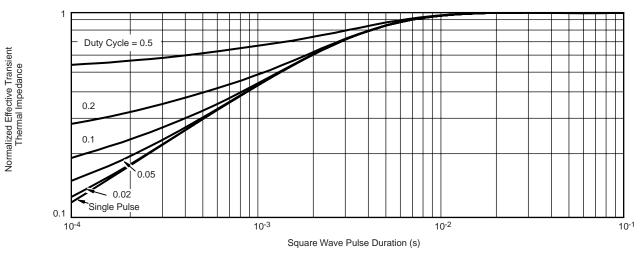


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





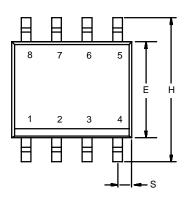
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







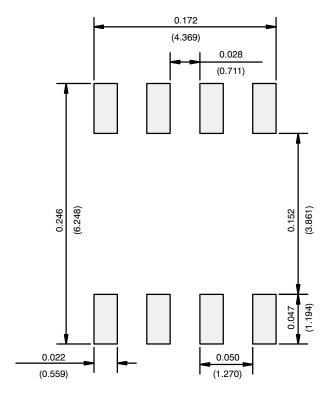
	MILLIM	IETERS	INCHES		
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sen-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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